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Behzad Razavi

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Printed in the United States of America 10 9 8 7 6 5 4 3 2 1

ISBN 0-7803-1093-4

**IEEE Order Number: PC4465** 

#### Library of Congress Cataloging-in-Publication Data

Razaví, Behzad.

Principles of data conversion system design / Behzad Razavi.

Includes bibliographical references and index. ISBN 0-7803-1093-4

1. Analog-to-digital converters—design and construction.

2. Digital-to-analog converters-Design and construction.

Integrated circuits—Design and construction. I. Title.

TK7887.6.R39 1995 94-26694

621.39'814-dc20

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